



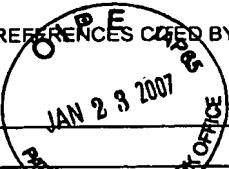
SHEET 1 OF 1

Form PTO 1449 (Modified)		ATTY DOCKET NO. 217623US2S DIV	SERIAL NO. 10/058,099			
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Hideo ANDO, et al.				
		FILING DATE January 29, 2002		GROUP 2615		
<b>U.S. PATENT DOCUMENTS</b>						
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
/SH/	AA	5,778,142	7Jul98	TAIRA, et al.		
/SH/	AB	5,915,067	22Jun99	NONOMURA, et al.		
/SH/	AC	5,999,696	7Dec99	TSUGA, et al.		
/SH/	AD	5,999,698	7Dec99	NAKAI, et al.		
/SH/	AE	6,088,507	11Jul00	YAMAUCHI, et al.		
/SH/	AF	6,094,414	25Jul00	TAIRA, et al.		
/SH/	AG	6,112,011	29Aug00	HISATOMI		
/SH/	AH	6,198,874 B1	6Mar01	KANESHIGE, et al.		
/SH/	AI	6,222,806	24Apr01	MORI, et al.		
	AJ					
	AK					
	AL					
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<b>FOREIGN PATENT DOCUMENTS</b>						
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
/SH/	AO	JP 8-263969	11Oct96	JAPAN	<input checked="" type="checkbox"/> YES	<input type="checkbox"/> NO
/SH/	AP	JP 60-236163	22Nov85	JAPAN (English Abstract of Japanese Patent)	<input type="checkbox"/> YES	<input checked="" type="checkbox"/> NO
/SH/	AQ	JP 58-088978	27May83	JAPAN (English Abstract of Japanese Patent)	<input type="checkbox"/> YES	<input checked="" type="checkbox"/> NO
/SH/	AR	JP 02-206820	16Aug90	JAPAN (English Abstract of Japanese Patent)	<input type="checkbox"/> YES	<input checked="" type="checkbox"/> NO
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	AU				<input type="checkbox"/> YES	<input type="checkbox"/> NO
	AV				<input type="checkbox"/> YES	<input type="checkbox"/> NO
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>						
	AW	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 1998-133832 (with English translation)				
	AX					
	AY					
	AZ				<input type="checkbox"/> Additional References sheet(s) attached	
Examiner /Syed Hasan/				Date Considered 10/29/2007		
<p>*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>						

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LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Hideo ANDO, et al.					
		FILING DATE January 29, 2002		GROUP 2621			
		<b>U.S. PATENT DOCUMENTS</b>					
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
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<b>FOREIGN PATENT DOCUMENTS</b>							
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/SH/	AO	3898751	03/28/07	JAPAN	YES	NO	
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	AQ						
	AR						
	AS						
	AT						
	AU						
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<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
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	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner				/Syed Hasan/		Date Considered	
						10/29/2007	

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LIST OF REFERENCES CITED BY APPLICANT  		APPLICANT		Hideo ANDO, et al.			
		FILING DATE		GROUP			
		January 29, 2002		2621			
U.S. PATENT DOCUMENTS							
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/SH/	AO 6-223504	08/12/94	Japan		YES	NO	X
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AQ							
AR							
AS							
AT							
AU							
AV							
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
AW							
AX							
AY							
AZ	<input type="checkbox"/> Additional References sheet(s) attached						
Examiner /Syed Hasan/				Date Considered 10/29/2007			

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SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 217623US2SDIV	PATENT & TRADEMARK OFFICE		SERIAL NO. 10/058,099
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT		Hideo ANDO, et al.			
		FILING DATE		GROUP		January 29, 2002	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
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/SH/	AO	11-238318	08/31/1999	JAPAN			X
/SH/	AP	8-315551	11/29/1996	JAPAN			X
/SH/	AQ	9-135412	05/20/1997	JAPAN			X
/SH/	AR	10-112166	04/28/1998	JAPAN			X
/SH/	AS	11-162119	06/18/1999	JAPAN			X
	AT						
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	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
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	AZ						<input type="checkbox"/> Additional References sheet(s) attached
Examiner		/Syed Hasan/			Date Considered		10/29/2007
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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Attorney Docket No. 2 23US-2S DIV

## Notice of References Cited

Application/Control No.	Applicant(s)/Patent Under Reexamination
New Divisional App.	ANDO ET AL
Examiner	Art Unit
To Be Assigned	Unassigned

Page 1 of 1

### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
SH	A	US-6,212,330-B1	04-2001	Yamamoto et al	386	95
SH	B	US-6,181,870-B1	01-2001	Okada et al	386	95
	C	US- -				
	D	US- -				
	E	US- -				
	F	US- -				
	G	US- -				
	H	US- -				
	I	US- -				
	J	US- -				
	K	US- -				
	L	US- -				
	M	US- -				

### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	- -				
	O	- -				
	P	- -				
	Q	- -				
	R	- -				
	S	- -				
	T	- -				

### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
	U		
	V		
	W		
	X		

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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Form PTO 1440 (Modified)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY DOCKET NO. 217623US-2SDIV	SERIAL NO. New Divisional Application
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT	Hideo ANDO, et al.
		FILING DATE HEREWITH	GROUP To be assigned

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
AA						
AB						
AC						
AD						
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AG						
AH						
AI						
AJ						
AK						
AL						
AM						
AN						

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO
/SH/	AO 58-68978	5/27/83	Japan		X
/SH/	AP 60-236163	11/22/85	Japan		X
/SH/	AQ 2-206820	8/16/80	Japan		X
AR					
AS					
AT					
AU					
AV					

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

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AX	
AY	
AZ	

Examiner /Syed Hasan/ Date Considered 10/29/2007

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